

SUPPORTING INFORMATION

Incident Angle Dependence of the Waveform of the Polarization-Sensitive Photoresponse in CuSe/Se Thin Film

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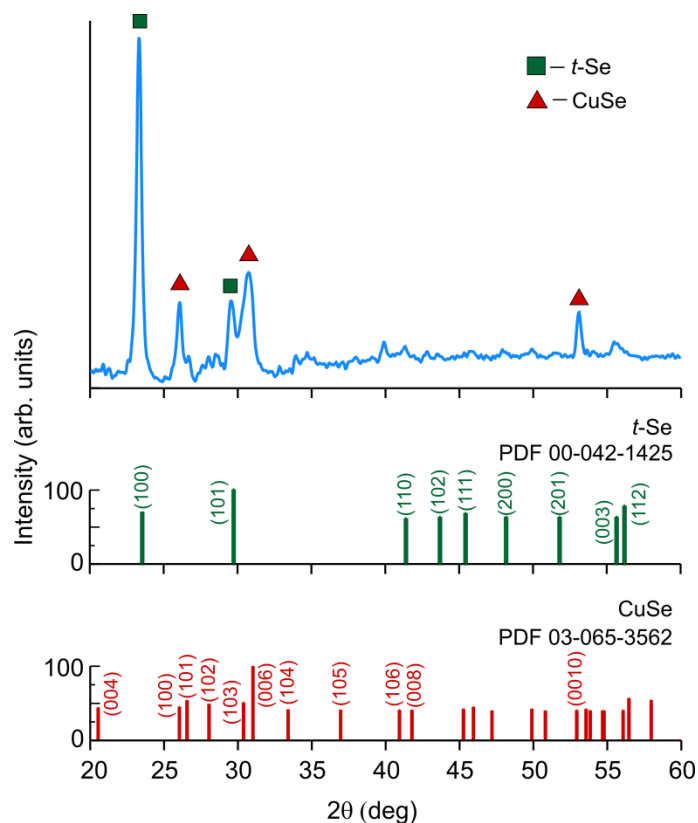


Figure S1. X-ray diffractogram of the CuSe/t-Se nanocomposite film and diffraction patterns of CuSe (PDF 00-034-0171) and t-Se (PDF 00-042-1425) powders. A copper-based X-ray tube generating radiation at a wavelength of 0.1541 nm was used.

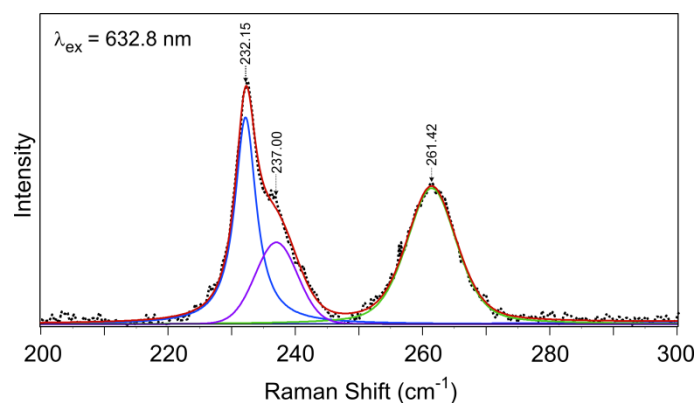


Figure S2. Raman spectrum of the CuSe/*t*-Se nanocomposite film (black line). The red line represents the fitting of the combined Gaussian profiles at (blue line) 232 and (purple line) 237 cm^{-1} corresponding to the *t*-Se and (green line) 262 cm^{-1} to the CuSe nanocrystallites Raman resonances. A He-Ne laser radiation at a wavelength of 632.8 nm as excitation pumping was used.

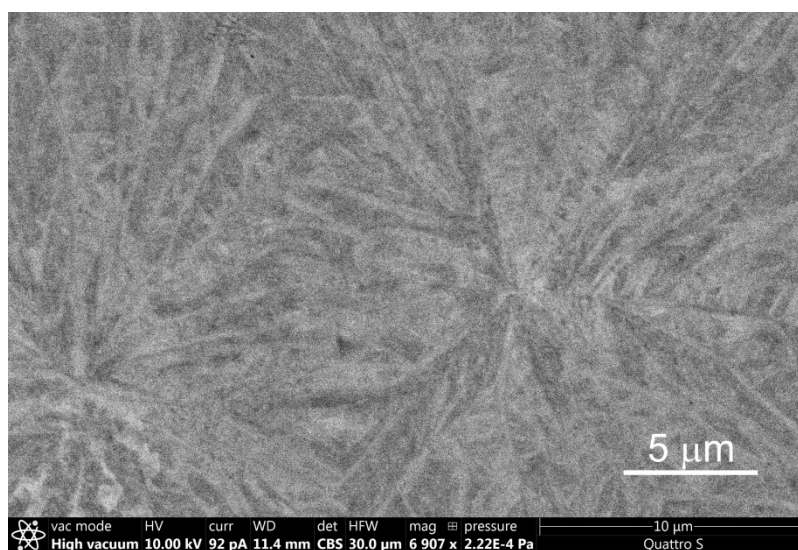


Figure S3. Scanning electron microscope image of the CuSe/*t*-Se semitransparent thin film surface.

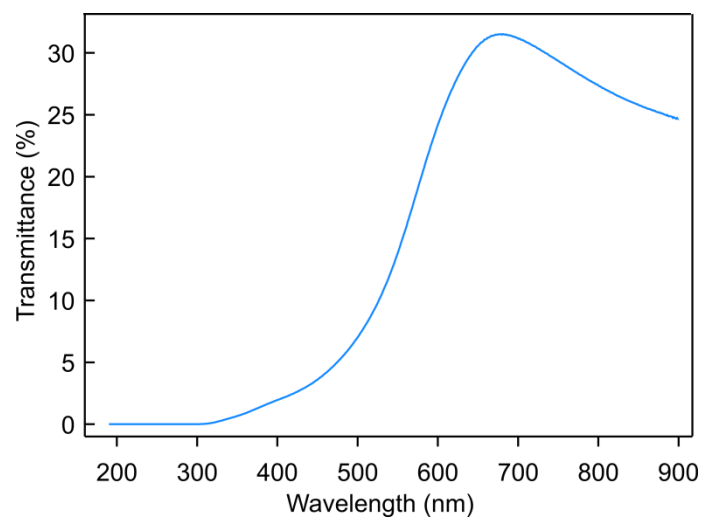


Figure S4. The optical transmittance spectrum of the CuSe/*t*-Se nanocomposite.